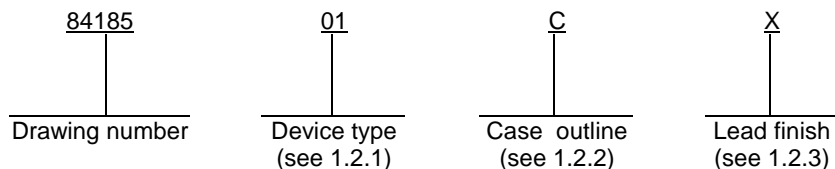


REVISIONS																			
LTR	DESCRIPTION	DATE (YR-MO-DA)	APPROVED																
A	Add vendor CAGE 27014. Add case outline I (metal can). Add terminal connections for case H. Delete testing for R <sub>OUT</sub> , V <sub>N</sub> , C <sub>IN</sub> , B <sub>W1</sub> , B <sub>W2</sub> , B <sub>W3</sub> , t <sub>PD-1</sub> , t <sub>PD-3</sub> , t <sub>R-1</sub> , t <sub>R-3</sub> . Editorial changes throughout.	86-05-12	M. A. FRYE																
B	Add vendor CAGE 18324. Add device 02, generic part number 592. Delete vendor CAGE 27014 for device 01IX. Change to military drawing format. Make changes to table I. Editorial changes throughout. Delete vendor CAGE 01295 for device 01IX. Inactivate device 01HX for new design.	89-05-09	M. A. FRYE																
C	Add device 03 for generic part number TL027. Add outline letter 2. Make changes to t <sub>PD</sub> and t <sub>R2</sub> . Inactivate device types 02HX and 02IX for new design.	93-11-30	M. A. FRYE																
D	Drawing updated to reflect current requirements. -rrp	03-01-10	R. MONNIN																
REV																			
SHEET																			
REV																			
SHEET																			
REV STATUS OF SHEETS				REV	D	D	D	D	D	D	D	D	D	D					
				SHEET	1	2	3	4	5	6	7	8							
PMIC N/A				PREPARED BY RICK C. OFFICER				<b>DEFENSE SUPPLY CENTER COLUMBUS</b> <b>COLUMBUS, OHIO 43216</b> <a href="http://www.dscc.dla.mil">http://www.dscc.dla.mil</a>  <b>MICROCIRCUIT, LINEAR, TWO-STAGE</b> <b>DIFFERENTIAL VIDEO AMPLIFIER, MONOLITHIC SILICON</b>											
<b>STANDARD MICROCIRCUIT DRAWING</b>  THIS DRAWING IS AVAILABLE FOR USE BY ALL DEPARTMENTS AND AGENCIES OF THE DEPARTMENT OF DEFENSE  AMSC N/A				CHECKED BY RAY MONNIN															
				APPROVED BY MICHAEL A. FRYE															
				DRAWING APPROVAL DATE 85-10-04															
				REVISION LEVEL D		SIZE A	CAGE CODE <b>67268</b>	<b>84185</b>											
						SHEET		1 OF 8											

1. SCOPE

1.1 Scope. This drawing describes device requirements for MIL-STD-883 compliant, non-JAN class level B microcircuits in accordance with MIL-PRF-38535, appendix A.

1.2 Part or Identifying Number (PIN). The complete PIN is as shown in the following example:



1.2.1 Device type(s). The device type(s) identify the circuit function as follows:

<u>Device type</u>	<u>Generic number</u>	<u>Circuit function</u>
01	733	Two-stage, differential input, differential output video amplifier
02	592	Two-stage, differential input, differential output video amplifier
03	TL027	Two-stage, differential input, differential output video amplifier

1.2.2 Case outline(s). The case outline(s) are as designated in MIL-STD-1835 and as follows:

<u>Outline letter</u>	<u>Descriptive designator</u>	<u>Terminals</u>	<u>Package style</u>
C	GDIP1-T14 or CDIP2-T14	14	Dual-in-line
H	GDFP1-F10 or CDFP2-F10	10	Flat pack
I	MACY1-X10	10	Can
2	CQCC1-N20	20	Square leadless chip carrier

1.2.3 Lead finish. The lead finish is as specified in MIL-PRF-38535, appendix A.

1.3 Absolute maximum ratings.

Positive supply voltage (+V <sub>CC</sub> ) .....	+8 V dc
Negative supply voltage (-V <sub>CC</sub> ) .....	-8 V dc
Differential input voltage .....	±5 V dc
Common mode input voltage .....	±6 V dc
Output current .....	10 mA
Power dissipation (P <sub>D</sub> ) .....	500 mW <u>1/</u>
Junction temperature (T <sub>J</sub> ) .....	+150°C
Storage temperature range .....	-65°C to +150°C
Lead temperature (soldering, 10 seconds) .....	+300°C
Thermal resistance, junction-to-ambient (θ <sub>JC</sub> ) .....	See MIL-STD-1835

1.4 Recommended operating conditions.

Ambient operating temperature range (T <sub>A</sub> ) .....	-55°C to +125°C
-------------------------------------------------------------	-----------------

1/ With T<sub>A</sub> above +105°C, derate linearly 11 mW/°C for cases C and 2. With T<sub>A</sub> above +57°C, derate linearly 5.5 mW/°C for case H. With T<sub>A</sub> above +75°C, derate linearly 6.5 mW/°C for case I.

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2. APPLICABLE DOCUMENTS

2.1 Government specification, standards, and handbooks. The following specification, standards, and handbooks form a part of this drawing to the extent specified herein. Unless otherwise specified, the issues of these documents are those listed in the issue of the Department of Defense Index of Specifications and Standards (DoDISS) and supplement thereto, cited in the solicitation.

SPECIFICATION

DEPARTMENT OF DEFENSE

MIL-PRF-38535 -- Integrated Circuits, Manufacturing, General Specification for.

STANDARDS

DEPARTMENT OF DEFENSE

MIL-STD-883 - Test Method Standard Microcircuits.  
MIL-STD-1835 - Interface Standard Electronic Component Case Outlines.

HANDBOOKS

DEPARTMENT OF DEFENSE

MIL-HDBK-103 -- List of Standard Microcircuit Drawings.  
MIL-HDBK-780 - Standard Microcircuit Drawings.

(Unless otherwise indicated, copies of the specification, standards, and handbooks are available from the Standardization Document Order Desk, 700 Robbins Avenue, Building 4D, Philadelphia, PA 19111-5094.)

2.2 Order of precedence. In the event of a conflict between the text of this drawing and the references cited herein, the text of this drawing takes precedence. Nothing in this document, however, supersedes applicable laws and regulations unless a specific exemption has been obtained.

3. REQUIREMENTS

3.1 Item requirements. The individual item requirements shall be in accordance with MIL-PRF-38535, appendix A for non-JAN class level B devices and as specified herein. Product built to this drawing that is produced by a Qualified Manufacturer Listing (QML) certified and qualified manufacturer or a manufacturer who has been granted transitional certification to MIL-PRF-38535 may be processed as QML product in accordance with the manufacturers approved program plan and qualifying activity approval in accordance with MIL-PRF-38535. This QML flow as documented in the Quality Management (QM) plan may make modifications to the requirements herein. These modifications shall not affect form, fit, or function of the device. These modifications shall not affect the PIN as described herein. A "Q" or "QML" certification mark in accordance with MIL-PRF-38535 is required to identify when the QML flow option is used.

3.2 Design, construction, and physical dimensions. The design, construction, and physical dimensions shall be as specified in MIL-PRF-38535, appendix A and herein.

3.2.1 Case outline(s). The case outline(s) shall be in accordance with 1.2.2 herein.

3.2.2 Terminal connections. The terminal connections shall be as specified on figure 1.

3.3 Electrical performance characteristics. Unless otherwise specified herein, the electrical performance characteristics are as specified in table I and shall apply over the full ambient operating temperature range.

3.4 Electrical test requirements. The electrical test requirements shall be the subgroups specified in table II. The electrical tests for each subgroup are described in table I.

3.5 Marking. Marking shall be in accordance with MIL-PRF-38535, appendix A. The part shall be marked with the PIN listed in 1.2 herein. In addition, the manufacturer's PIN may also be marked as listed in MIL-HDBK-103 (see 6.6 herein). For packages where marking of the entire SMD PIN number is not feasible due to space limitations, the manufacturer has the option of not marking the "5962-" on the device.

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TABLE I. Electrical performance characteristics.

Test	Symbol	Conditions <u>1/</u> -55°C ≤ T <sub>A</sub> ≤ +125°C unless otherwise specified	Group A subgroups	Device type	Limits		Unit
					Min	Max	
Input voltage range	V <sub>IN</sub>		1, 2, 3	All	±1.0		V
Input offset current	I <sub>IO</sub>		1	01, 02		3	μA
			2, 3			5	
			1	03		5	
			2, 3			6	
Input bias current	I <sub>IB</sub>		1	01, 03		30	μA
				02		20	
			2, 3	All		40	
Input resistance	R <sub>IN2</sub>	<u>2/ 3/</u>	1	01, 02	20		kΩ
			2, 3			8	
			1	03	10		
			2, 3			8	
Output offset voltage	V <sub>OO1</sub>	R <sub>L</sub> = ∞ <u>4/</u>	1, 2, 3	All		2.0	V
			1	01, 02		1.0	
	2, 3				1.2		
	1	03		0.75			
			2, 3		1.5		
	V <sub>OO3</sub>	R <sub>L</sub> = ∞ <u>5/</u>	1	01		1.0	
2, 3					1.2		
Output common mode voltage	V <sub>OCM</sub>	R <sub>L</sub> = ∞, T <sub>A</sub> = +25°C	1	01, 02		3.4	V
				03		4.25	
Change in output common mode voltage	ΔV <sub>OCM</sub>	R <sub>L</sub> = ∞, T <sub>A</sub> = +25°C, V <sub>AGC</sub> = 0 V to 2 V	1	03		300	mV
Open circuit voltage at REF OUT	V <sub>REF</sub>	I <sub>REF</sub> = 1 mA to 100 μA, T <sub>A</sub> = +25°C	1	03	1.3	1.5	V
Output sink current	I <sub>SINK</sub>		1	01, 02	2.5		mA
			2, 3			2.2	
			1	03	3		
			2, 3			2.8	
Supply current	I <sub>CC</sub>		1	01, 02		24	mA
			2, 3			27	
			1	03		27	
			2, 3			30	
Supply voltage rejection ratio	S <sub>VRR</sub>	±5.5 V ≤ V <sub>CC</sub> ≤ ±6.5 V	4, 5, 6	All	50		dB
Common mode rejection ratio	C <sub>MRR</sub>	-1 V ≤ V <sub>CM</sub> ≤ +1 V, f ≤ 100 kHz	4	All	60		dB
			5, 6		50		

See footnotes at end of table.

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TABLE I. Electrical performance characteristics – Continued.

Test	Symbol	Conditions <u>1/</u> -55°C ≤ T <sub>A</sub> ≤ +125°C unless otherwise specified	Group A subgroups	Device type	Limits		Unit
					Min	Max	
Output voltage swing	V <sub>OUT</sub>	R <sub>L</sub> = 2 kΩ	4	01, 02	2.5		V <sub>P-P</sub>
			5, 6		2.2		
			4	03	3		
			5, 6		2.8		
Differential voltage gain	A <sub>V1</sub>	V <sub>OUT</sub> = 3.0 V <sub>P-P</sub> , <u>4/</u> R <sub>L</sub> = 2 kΩ	4	01	300	500	V/V
			5, 6		200	600	
			4	02	300	500	
			5, 6		200	600	
			4	03	200	400	
			5, 6		150	450	
	A <sub>V2</sub>	V <sub>OUT</sub> = 3.0 V <sub>P-P</sub> , <u>2/</u> R <sub>L</sub> = 2 kΩ	4	01	90	110	
			5, 6		80	120	
			4	02	90	110	
			5, 6		80	120	
			4	03	65	105	
			5, 6		55	115	
	A <sub>V3</sub>	V <sub>OUT</sub> = 3.0 V <sub>P-P</sub> , <u>5/</u> R <sub>L</sub> = 2 kΩ	4	01	9	11	
			5, 6		8	12	
Propagation delay	t <sub>PD</sub>	V <sub>OUT</sub> = 1 V <sub>P-P</sub> , <u>2/</u> <u>3/</u> T <sub>A</sub> = +25°C	9	All		10	ns
Rise time	t <sub>r2</sub>	V <sub>OUT</sub> = 1 V <sub>P-P</sub> , <u>2/</u> <u>3/</u> T <sub>A</sub> = +25°C	9	01, 02		10	ns
				03		12	

1/ V<sub>S</sub> = ±6.0 V. Unless otherwise specified, for device type 03, AGC = 0 V, and REF OUT pin is open.

2/ GAIN ADJ 2A and GAIN ADJ 2B connected together. Gain = 100.

3/ If not tested, shall be guaranteed to the limits specified in table I herein.

4/ GAIN ADJ 1A and GAIN ADJ 1B connected together. Gain = 400.

5/ All gain pins open. Gain = 10.

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Device types	01 and 02	03	01 and 02	01 and 02	01 and 02	03
Case outlines	C		H	I	2	
Terminal number	Terminal symbol					
1	INPUT+	INPUT+	INPUT-	INPUT-	NC	NC
2	NC	AGC	GAIN ADJ 2A	INPUT+	INPUT+	INPUT+
3	GAIN ADJ 2A	GAIN ADJ 1A	GAIN ADJ 1A	GAIN ADJ 2A	NC	AGC
4	GAIN ADJ 1A	GAIN ADJ 2A	-V <sub>CC</sub>	GAIN ADJ 1A	GAIN ADJ 2A	GAIN ADJ 1A
5	-V <sub>CC</sub>	-V <sub>CC</sub>	OUTPUT+	-V <sub>CC</sub>	NC	NC
6	NC	NC	OUTPUT-	OUTPUT+	GAIN ADJ 1A	GAIN ADJ 2A
7	OUTPUT+	OUTPUT+	+V <sub>CC</sub>	OUTPUT-	NC	NC
8	OUTPUT-	OUTPUT-	GAIN ADJ 1B	+V <sub>CC</sub>	-V <sub>CC</sub>	-V <sub>CC</sub>
9	NC	NC	GAIN ADJ 2B	GAIN ADJ 1B	NC	NC
10	+V <sub>CC</sub>	+V <sub>CC</sub>	-INPUT	GAIN ADJ 2B	OUTPUT+	OUTPUT+
11	GAIN ADJ 1B	GAIN ADJ 2B	----	----	NC	NC
12	GAIN ADJ 2B	GAIN ADJ 1B	----	----	OUTPUT-	OUTPUT-
13	NC	REF OUT	----	----	NC	NC
14	INPUT-	INPUT-	----	----	+V <sub>CC</sub>	+V <sub>CC</sub>
15	----	----	----	----	NC	NC
16	----	----	----	----	GAIN ADJ 1B	GAIN ADJ 2B
17	----	----	----	----	NC	NC
18	----	----	----	----	GAIN ADJ 2B	GAIN ADJ 1B
19	----	----	----	----	NC	REF OUT
20	----	----	----	----	INPUT-	INPUT-

NC = No connection

FIGURE 1. Terminal connections.

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3.5.1 Certification/compliance mark. A compliance indicator "C" shall be marked on all non-JAN devices built in compliance to MIL-PRF-38535, appendix A. The compliance indicator "C" shall be replaced with a "Q" or "QML" certification mark in accordance with MIL-PRF-38535 to identify when the QML flow option is used.

3.6 Certificate of compliance. A certificate of compliance shall be required from a manufacturer in order to be listed as an approved source of supply in MIL-HDBK-103 (see 6.6 herein). The certificate of compliance submitted to DSCC-VA prior to listing as an approved source of supply shall affirm that the manufacturer's product meets the requirements of MIL-PRF-38535, appendix A and the requirements herein.

3.7 Certificate of conformance. A certificate of conformance as required in MIL-PRF-38535, appendix A shall be provided with each lot of microcircuits delivered to this drawing.

3.8 Notification of change. Notification of change to DSCC-VA shall be required in accordance with MIL-PRF-38535, appendix A.

3.9 Verification and review. DSCC, DSCC's agent, and the acquiring activity retain the option to review the manufacturer's facility and applicable required documentation. Offshore documentation shall be made available onshore at the option of the reviewer.

#### 4. QUALITY ASSURANCE PROVISIONS

4.1 Sampling and inspection. Sampling and inspection procedures shall be in accordance with MIL-PRF-38535, appendix A.

4.2 Screening. Screening shall be in accordance with method 5004 of MIL-STD-883, and shall be conducted on all devices prior to quality conformance inspection. The following additional criteria shall apply:

a. Burn-in test, method 1015 of MIL-STD-883.

(1) Test condition A, B, C, or D. The test circuit shall be maintained by the manufacturer under document revision level control and shall be made available to the preparing or acquiring activity upon request. The test circuit shall specify the inputs, outputs, biases, and power dissipation, as applicable, in accordance with the intent specified in test method 1015 of MIL-STD-883.

(2)  $T_A = +125^\circ\text{C}$ , minimum.

b. Interim and final electrical test parameters shall be as specified in table II herein, except interim electrical parameter tests prior to burn-in are optional at the discretion of the manufacturer.

4.3 Quality conformance inspection. Quality conformance inspection shall be in accordance with method 5005 of MIL-STD-883 including groups A, B, C, and D inspections. The following additional criteria shall apply.

##### 4.3.1 Group A inspection.

a. Tests shall be as specified in table II herein.

b. Subgroups 7, 8, 10, and 11 in table I, method 5005 of MIL-STD-883 shall be omitted.

##### 4.3.2 Groups C and D inspections.

a. End-point electrical parameters shall be as specified in table II herein.

b. Steady-state life test conditions, method 1005 of MIL-STD-883.

(1) Test condition A, B, C, or D. The test circuit shall be maintained by the manufacturer under document revision level control and shall be made available to the preparing or acquiring activity upon request. The test circuit shall specify the inputs, outputs, biases, and power dissipation, as applicable, in accordance with the intent specified in test method 1005 of MIL-STD-883.

(2)  $T_A = +125^\circ\text{C}$ , minimum.

(3) Test duration: 1,000 hours, except as permitted by method 1005 of MIL-STD-883.

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TABLE II. Electrical test requirements.

MIL-STD-883 test requirements	Subgroups (in accordance with MIL-STD-883, method 5005, table I)
Interim electrical parameters (method 5004)	----
Final electrical test parameters (method 5004)	1*, 2, 3, 4
Group A test requirements (method 5005)	1, 2, 3, 4, 5, 6, 9**
Groups C and D end-point electrical parameters (method 5005)	1

\* PDA applies to subgroup 1.

\*\* Subgroup 9, if not tested, shall be guaranteed to the limits specified in table I.

5. PACKAGING

5.1 Packaging requirements. The requirements for packaging shall be in accordance with MIL-PRF-38535, appendix A.

6. NOTES

6.1 Intended use. Microcircuits conforming to this drawing are intended for use for Government microcircuit applications (original equipment), design applications, and logistics purposes.

6.2 Replaceability. Microcircuits covered by this drawing will replace the same generic device covered by a contractor-prepared specification or drawing.

6.3 Configuration control of SMD's. All proposed changes to existing SMD's will be coordinated with the users of record for the individual documents. This coordination will be accomplished using DD Form 1692, Engineering Change Proposal.

6.4 Record of users. Military and industrial users shall inform Defense Supply Center Columbus when a system application requires configuration control and the applicable SMD. DSCC will maintain a record of users and this list will be used for coordination and distribution of changes to the drawings. Users of drawings covering microelectronics devices (FSC 5962) should contact DSCC-VA, telephone (614) 692-0544.

6.5 Comments. Comments on this drawing should be directed to DSCC-VA, Columbus, Ohio 43216-5000, or telephone (614) 692-0547.

6.6 Approved sources of supply. Approved sources of supply are listed in MIL-HDBK-103. The vendors listed in MIL-HDBK-103 have agreed to this drawing and a certificate of compliance (see 3.6 herein) has been submitted to and accepted by DSCC-VA.

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STANDARD MICROCIRCUIT DRAWING BULLETIN

DATE: 03-01-10

Approved sources of supply for SMD 84185 are listed below for immediate acquisition information only and shall be added to MIL-HDBK-103 and QML-38535 during the next revision. MIL-HDBK-103 and QML-38535 will be revised to include the addition or deletion of sources. The vendors listed below have agreed to this drawing and a certificate of compliance has been submitted to and accepted by DSCC-VA. This bulletin is superseded by the next dated revision of MIL-HDBK-103 and QML-38535.

Standard microcircuit drawing PIN <u>1</u> /	Vendor CAGE number	Vendor similar PIN <u>2</u> /
8418501CA	<u>3</u> /	UA733MJB
	<u>3</u> /	1733/BCAJC
8418501HA	<u>3</u> /	UA733MUB
8418501IA	<u>3</u> /	1733/BIAJC
84185012A	<u>3</u> /	UA733MFKB
8418502CA	<u>3</u> /	SE592MJB
	<u>3</u> /	592/BCA
8418502HA	<u>3</u> /	SE592MUB
8418502IA	<u>3</u> /	SE592MLB
84185022A	<u>3</u> /	SE592MFKB
8418503CA	<u>3</u> /	TL027MJB
84185032A	<u>3</u> /	TL027MFKB

- 1/ The lead finish shown for each PIN representing a hermetic package is the most readily available from the manufacturer listed for that part. If the desired lead finish is not listed contact the vendor to determine its availability.
- 2/ **Caution.** Do not use this number for item acquisition. Items acquired to this number may not satisfy the performance requirements of this drawing.
- 3/ Not available from an approved source of supply.

The information contained herein is disseminated for convenience only and the Government assumes no liability whatsoever for any inaccuracies in the information bulletin.